

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	758	(clock same simulat\$5) and global and local	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/03/16 19:08
L2	2018	grid same clock	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/03/16 19:34
L3	191	(clock same simulat\$5) and global and local and arrival	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/03/16 19:58
L4	31	(clock same simulat\$5) and global and local and arrival and slope	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/03/16 19:55
L5	4	(clock same simulat\$5) and global and local and arrival and slope and insert and buffer and extract\$4 and skew	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/03/16 19:59
L8	3	(grid same clock) and global and local and arrival and slope and insert and buffer and extract\$4 and skew	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/03/16 19:57
L9	12	(clock same global) and (clock same local) and arrival and slope and insert and buffer and extract\$4 and skew	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/03/16 19:58
L10	3	(grid same base) and clock and global and local and arrival and slope and insert and buffer and extract\$4 and skew	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/03/16 20:01
L15	3	(grid same clock) and global and local and arrival and slope and insert and buffer and extract\$4 and skew and simulat\$4	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/03/16 20:01

	Document ID	Title	Current OR
1	US 20040201939 A1	Clock trim mechanism for onboard system clock	361/104
2	US 20040201647 A1	Stitching of integrated circuit components	347/54
3	US 20040199786 A1	Randomisation of the location of secret information on each of a series of integrated circuits	713/200
4	US 20040196320 A1	Dead nozzle compensation	347/12
5	US 20040193880 A1	Authenticated communication between multiple entities	713/168
6	US 20040189731 A1	Fixative compensation	347/19
7	US 20040189355 A1	Temperature based filter for an on-chip system clock	327/138
8	US 20040181303 A1	Relatively unique ID in integrated circuit	700/115
9	US 20040174570 A1	Variable size dither matrix usage	358/3.13
10	US 20030074643 A1	Unified database system to store, combine, and manipulate clock related data for grid-based clock distribution design	716/6
11	US 20030074642 A1	Clock skew verification methodology for grid-based design	716/6
12	US 20030074175 A1	Simulation by parts method for grid-based clock distribution design	703/19